Serial ATA International Organization:

Serial ATA Interoperability Program Revision 1.1
Defined Waiver List Version 1.0

1-March-2007

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Serial ATA International Organization: Serial ATA Interoperability Program Unified Test Document is available for download at www.sata-io.org.

For more information about Serial ATA, refer to the Serial ATA International Organization website at www.sata-io.org.

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Version History

Version	Date	Comments
1.0	03/01/2007	Initial ratified version.

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1. Overview

This document describes the policies and procedures developed for the Serial ATA Interoperability Program revision 1.1 by the Serial ATA International Organization (SATA-IO). The detailed Serial ATA specification requirements and Integrators List (IL) requirements will not be outlined in this document.

1.1. References

The policies and procedures defined here are constructed in reference to the following other documentation:

- Serial ATA Revision 2.5
- Serial ATA Interoperability Program Unified Test Document revision 1.1

1.2. Definitions, abbreviations, and conventions

1.2.1. Keywords

Several keywords are used to differentiate between different levels of requirements and optionality.

1.2.1.1. mandatory

A keyword indicating items to be implemented as defined by this standard.

1.2.1.2. may

A keyword that indicates flexibility of choice with no implied preference.

1.2.1.3. optional

A keyword that describes features that is not required by this standard. However, if any optional feature defined by the standard is implemented, the feature shall be implemented in the way defined by the standard.

1.2.1.4. shall

A keyword indicating a mandatory requirement. Designers are required to implement all such mandatory requirements to ensure interoperability with other standard conformant products.

1.2.1.5. should

A keyword indicating flexibility of choice with a strongly preferred alternative. Equivalent to the phrase “it is recommended”.

1.2.2. Conventions

1.2.2.1. Waiver definition format

The labelling of each waiver will consist of an identifier (ID) and a title. The ID will be formatted as “WVXX-YYY” where XX is the Interop Program Revision being referenced (e.g. Revision 1.1) and YYY is the waiver ID number. The waiver ID number will increment as new waivers are introduced, regardless of the revision impacted (e.g. WV11-001, WV12-002, WV12-003).

2. Testing Waiver Definitions

2.1. WV11-001 : Consideration of 2ns measurement as pass/fail criteria for TX-01

This waiver is only applicable to test results gathered under Interop Program Revision 1.1 testing. It shall not apply to previous or latter revisions of testing.

Refer to section 2.12.1 in Serial ATA Interoperability Program Revision 1.1 Unified Test Document Version 1.0.

In evaluation of the pass/fail criteria for Transmit Pair Differential Impedance (TX-01), if the existing min/max results criteria result in a failure, then the 2ns measured result shall be taken into consideration. If the 2ns result is measured between 85 ohms and 115 ohms, then the assessment of TX-01 shall be “PASS”.

2.2. WV11-002 : Consideration of 2ns measurement as pass/fail criteria for RX-01

This waiver is only applicable to test results gathered under Interop Program Revision 1.1 testing. It shall not apply to previous or latter revisions of testing.

Refer to section 2.14.1 in Serial ATA Interoperability Program Revision 1.1 Unified Test Document Version 1.0.

In evaluation of the pass/fail criteria for Receive Pair Differential Impedance (RX-01), if the existing min/max results criteria result in a failure, then the 2ns measured result shall be taken into consideration. If the 2ns result is measured between 85 ohms and 115 ohms, then the assessment of RX-01 shall be “PASS”.